## Alireza Kashir

List of Publications by Year in descending order

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840776 752698 20 399 11 20 citations h-index g-index papers 20 20 20 242 docs citations times ranked citing authors all docs

#	Article	IF	CITATIONS
1	Large Remnant Polarization in a Wake-Up Free Hf <sub>0.5</sub> Zr <sub>0.5</sub> O <sub>2</sub> Ferroelectric Film through Bulk and Interface Engineering. ACS Applied Electronic Materials, 2021, 3, 629-638.	4.3	79
2	Hafnium Oxide (HfO $<$ sub $>2sub>) \hat{a}\in" A Multifunctional Oxide: A Review on the Prospect and Challenges of Hafnium Oxide in Resistive Switching and Ferroelectric Memories. Small, 2022, 18, e2107575.$	10.0	78
3	Defect Engineering to Achieve Wakeâ€up Free HfO <sub>2</sub> â€Based Ferroelectrics. Advanced Engineering Materials, 2021, 23, .	3.5	53
4	Effect of dead layers on the ferroelectric property of ultrathin HfZrOx film. Applied Physics Letters, 2020, 117, .	3.3	37
5	A new approach to achieving strong ferroelectric properties in TiN/Hf <sub>0.5</sub> Zr <sub>0.5</sub> O <sub>2</sub> /TiN devices. Nanotechnology, 2021, 32, 055703.	2.6	21
6	High polarization and wake-up free ferroelectric characteristics in ultrathin $Hf < sub > 0.5 < /sub > Zr < sub > 0.5 < /sub > O < sub > 2 < /sub > devices by control of oxygen-deficient layer. Nanotechnology, 2022, 33, 085206.$	2.6	21
7	Towards an ideal high-l̂º HfO <sub>2</sub> –ZrO <sub>2</sub> -based dielectric. Nanoscale, 2021, 13, 13631-13640.	5.6	18
8	Ferroelectric and Dielectric Properties of Hf <sub>0.5</sub> Zr <sub>0.5</sub> O <sub>2</sub> Thin Film Near Morphotropic Phase Boundary. Physica Status Solidi (A) Applications and Materials Science, 2021, 218, 2000819.	1.8	18
9	A CMOS-compatible morphotropic phase boundary. Nanotechnology, 2021, 32, 445706.	2.6	12
10	Hf <sub>1–<i>x</i></sub> Zr <sub><i>x</i></sub> O <sub>2</sub> /ZrO <sub>2</sub> Nanolaminate Thin Films as a High-κ Dielectric. ACS Applied Electronic Materials, 2021, 3, 5632-5640.	4.3	12
11	Dielectric Properties of Strained Nickel Oxide Thin Films. Journal of the Korean Physical Society, 2019, 74, 984-988.	0.7	11
12	Effects of high pressure oxygen annealing on Hf <sub>0.5</sub> Zr <sub>0.5</sub> O <sub>2</sub> ferroelectric device. Nanotechnology, 2021, 32, 315712.	2.6	11
13	A thin film perspective on quantum functional oxides. Current Applied Physics, 2019, 19, 207-214.	2.4	6
14	A grease for domain walls motion in HfO <sub>2</sub> -based ferroelectrics. Nanotechnology, 2022, 33, 155703.	2.6	6
15	Strain-Induced Increase of Dielectric Constant in EuO Thin Film. Materials Research Express, 2019, 6, 106321.	1.6	5
16	Pulsed Laser Deposition of Rocksalt Magnetic Binary Oxides. Thin Solid Films, 2019, 692, 137606.	1.8	5
17	Strain effect on magnetic-exchange-induced phonon splitting in NiO films. Journal of Physics Condensed Matter, 2020, 32, 405607.	1.8	2
18	Improvement of endurance and switching speed in Hf <sub>1â^'x </sub> Zr <sub>x</sub> O <sub>2</sub> thin films using a nanolaminate structure. Nanotechnology, 2022, 33, 395205.	2.6	2

#	Article	lF	CITATIONS
19	Spin-phonon interaction increased by compressive strain in antiferromagnetic MnO thin films. Journal of Physics Condensed Matter, 2020, 32, 175402.	1.8	1
20	Two-step deposition of TiN capping electrodes to prevent degradation of ferroelectric properties in an in-situ crystallized TiN/Hf <sub>0.5</sub> Zr <sub>0.5</sub> O <sub>2</sub> /TiN device. Nano Express, 2022, 3, 015004.	2.4	1